

FDG6320C Dual N & P Channel Digital FET

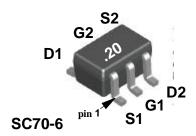
General Description

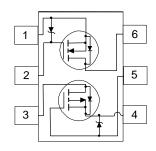
These dual N & P-Channel logic level enhancement mode field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. This device has been designed especially for low voltage applications as a replacement for bipolar digital transistors and small signal MOSFETS. Since bias resistors are not required, this dual digital FET can replace several different digital transistors, with different bias resistor values.

Features

- $\begin{array}{c} \blacksquare \quad \text{N-Ch 0.22 A, 25 V, R}_{\text{DS(ON)}} = 4.0 \; \Omega \; @ \; \text{V}_{\text{GS}} = 4.5 \; \text{V,} \\ \text{R}_{\text{DS(ON)}} = 5.0 \; \Omega \; @ \; \text{V}_{\text{GS}} = 2.7 \; \text{V.} \end{array}$
- Very small package outline SC70-6.
- Very low level gate drive requirements allowing direct operation in 3 V circuits (V_{GS(th)} < 1.5 V).
- Gate-Source Zener for ESD ruggedness (>6kV Human Body Model).







Absolute Maximum Ratings T_a = 25°C unless other wise noted

Symbol	Parameter	N-Channel	P-Channel	Units	
V _{DSS}	Drain-Source Voltage	25	-25	V	
V _{GSS}	Gate-Source Voltage	8	-8	V	
Drain Current - Continuous		0.22	-0.14	А	
	- Pulsed	0.65	-0.4		
P_{D}	Maximum Power Dissipation (Note 1)	0.3		W	
T _J ,T _{STG}	Operating and Storage Temperature Ranger	-55 to 150		°C	
ESD	Electrostatic Discharge Rating MIL-STD-883D Human Body Model (100pf / 1500 Ohm)	6		kV	
THERMAI	CHARACTERISTICS				
R	Thermal Resistance, Junction-to-Ambient (Note 1)	4	°C/W		

Symbol	Parameter	Conditions		Min	Тур	Max	Units	
OFF CHAR	ACTERISTICS		•					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	N-Ch	25			V	
300		$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	P-Ch	-25				
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I _D = 250 μA, Referenced to 25 °C	N-Ch		25		mV/°C	
		I _D =-250 μA, Referenced to 25 °C	P-Ch		-19			
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V},$	N-Ch			1	μA	
		T _J = 55°C				10		
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -20 \text{ V}, \ V_{GS} = 0 \text{ V},$	P-Ch			-1	μA	
		$T_{J} = 55^{\circ}C$				-10		
I _{GSS}	Gate - Body Leakage Current	$V_{GS} = 8 \text{ V}, \ V_{DS} = 0 \text{ V}$	N-Ch			100	nA	
		$V_{GS} = -8 \text{ V}, \ V_{DS} = 0 \text{ V}$	P-Ch			-100	nA	
ON CHARA	CTERISTICS (Note 2)			•	•			
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	N-Ch	0.65	0.85	1.5	V	
		$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	P-Ch	-0.65	-0.82	-1.5		
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I _D = 250 μA, Referenced to 25 °C	N-Ch		-2.1		mV/°C	
55(6)		I _D = -250 μA, Referenced to 25 °C	P-Ch		2.1			
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 0.22 \text{ A}$	N-Ch		2.6	4	Ω	
		T _J =125°C			5.3	7		
		$V_{GS} = 2.7 \text{ V}, I_D = 0.19 \text{ A}$			3.7	5		
		$V_{GS} = -4.5 \text{ V}, I_D = -0.14 \text{ A}$	P-Ch		7.3	10		
		T _J =125°C			11	17		
		$V_{GS} = -2.7 \text{ V}, I_{D} = -0.05 \text{ A}$			10.4	13		
$I_{D(ON)}$	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, \ V_{DS} = 5 \text{ V}$	N-Ch	0.22			Α	
		$V_{GS} = -4.5 \text{ V}, \ V_{DS} = -5 \text{ V}$	P-Ch	-0.14				
g _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 0.22 \text{ A}$	N-Ch		0.2		S	
		$V_{DS} = -5 \text{ V}, I_{D} = -0.14 \text{ A}$	P-Ch		0.12			
DYNAMIC C	HARACTERISTICS							
C _{iss}	Input Capacitance	N-Channel	N-Ch		9.5		pF	
		$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$	P-Ch		12			
C _{oss}	Output Capacitance	f = 1.0 MHz	N-Ch		6			
		P-Channel	P-Ch		7			
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$	N-Ch		1.3			
		f = 1.0 MHz	P-Ch		1.5			

Electrical Characteristics (continued)

SWITCHING CHARACTERISTICS (Note 2)

Symbol	Parameter	Conditions	Туре	Min	Тур	Max	Units
t _{D(on)}	Tum - On Delay Time	N-Channel	N-Ch		5	12	nS
		$V_{DD} = 5 \text{ V}, I_{D} = 0.5 \text{ A},$	P-Ch		5	12	
t,	Turn - On Rise Time	V_{GS} = 4.5 V, R_{GEN} = 50 Ω	N-Ch		4.5	10	nS
			P-Ch		8	16	
t _{D(off)}	Turn - Off Delay Time	P-Channel	N-Ch		4	8	nS
		$V_{DD} = -5 \text{ V}, I_{D} = -0.5 \text{ A},$	P-Ch		9	18	
t,	Turn - Off Fall Time	V_{GS} = -4.5 V, R_{GEN} = 50 Ω	N-Ch		3.2	7	nS
			P-Ch		5	12	
$\overline{Q_g}$	Total Gate Charge	N-Channel	N-Ch		0.29	0.4	nC
		$V_{DS} = 5 \text{ V}, I_{D} = 0.22 \text{ A},$	P-Ch		0.22	0.31	
Q_{gs}	Gate-Source Charge	V _{GS} = 4.5 V	N-Ch		0.12		nC
		P- Channel	P-Ch		0.12		
Q_{gd}	Gate-Drain Charge	$V_{DS} = -5 \text{ V}, I_{D} = -0.14 \text{ A},$	N-Ch		0.03		nC
		V _{GS} = -4.5 V	P-Ch		0.05		
DRAIN-SC	DURCE DIODE CHARACTERISTICS AND	MAXIMUM RATINGS					
Is	Maximum Continuous Drain-Source Diode	Forward Current	N-Ch			0.25	Α
			P-Ch			-0.25	
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 0.5 \text{ A} \text{ (Note 2)}$	N-Ch		8.0	1.2	V
		$V_{GS} = 0 \text{ V}, I_{S} = -0.5 \text{ A} \text{ (Note 2)}$	P-Ch		-0.8	-1.2	

^{1.} R_{g,M} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{g,C} is guaranteed by design while R_{RCA} is determined by the user's board design. $R_{\text{BJA}} = 415^{\circ}\text{C/W}$ on minimum mounting pad on FR-4 board in still air. 2. Pulse Test: Pulse Width $\leq 300 \mu \text{s}$, Duty Cycle $\leq 2.0\%$.

Typical Electrical Characteristics: N-Channel

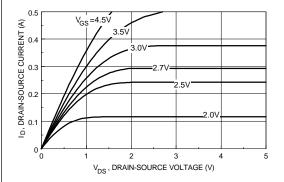


Figure 1. On-Region Characteristics.

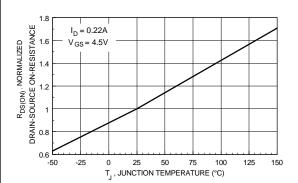


Figure 3. On-Resistance Variation with Temperature.

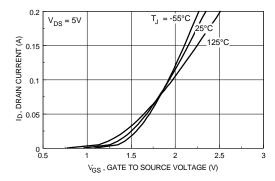


Figure 5. Transfer Characteristics.

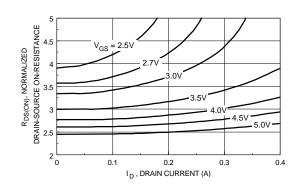


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

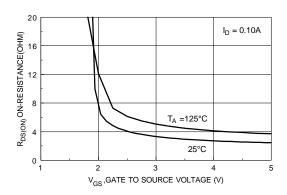


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

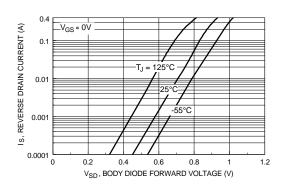


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Electrical Characteristics: N-Channel (continued)

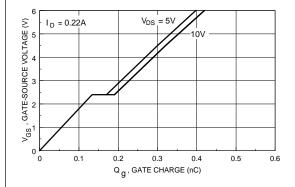


Figure 7. Gate Charge Characteristics.

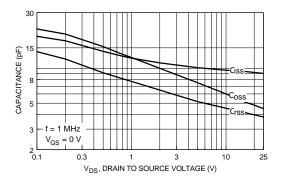


Figure 8. Capacitance Characteristics.

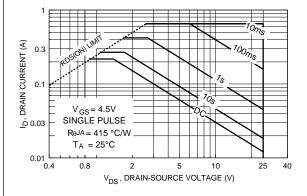


Figure 9. Maximum Safe Operating Area.

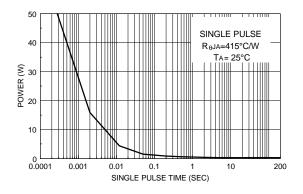


Figure 10. Single Pulse Maximum Power Dissipation.

Typical Electrical Characteristics: P-Channel

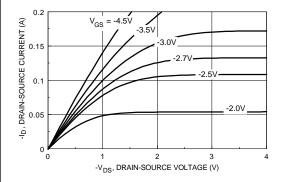


Figure 11. On-Region Characteristics.

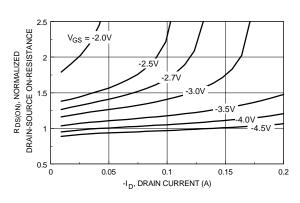


Figure 12. On-Resistance Variation with Drain Current and Gate Voltage.

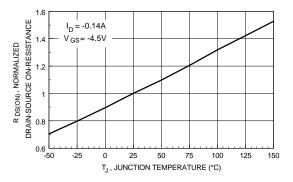


Figure 13. On-Resistance Variation with Temperature.

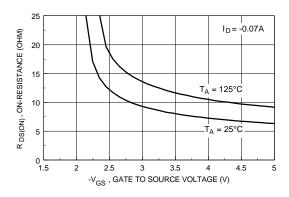


Figure 14. On-Resistance Variation with Gate-to-Source Voltage.

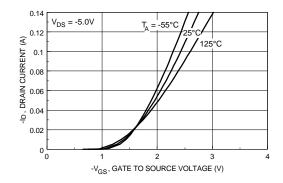


Figure 15. Transfer Characteristics.

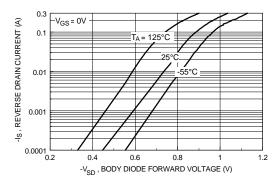


Figure 16. Body Diode Forward Voltage
Variation with Source Current
and Temperature.

Typical Electrical Characteristics: P-Channel (continued)

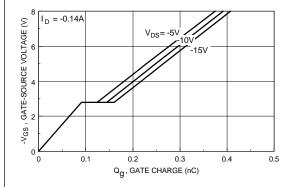


Figure 17. Gate Charge Characteristics.

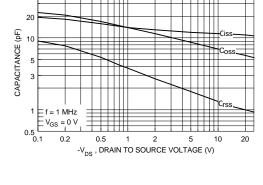


Figure 18. Capacitance Characteristics.

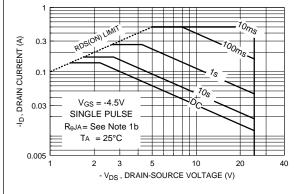


Figure 19. Maximum Safe Operating Area.

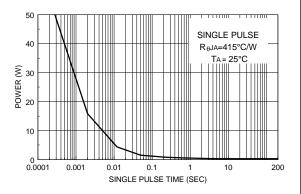


Figure 20. Single Pulse Maximum Power Dissipation.

Typical Thermal Characteristics: N & P-Channel (continued)

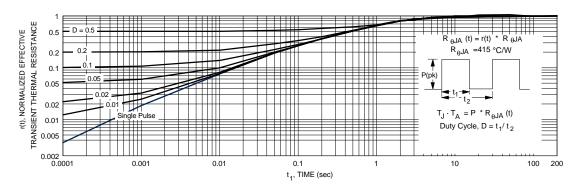


Figure 21. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in note 1. Transient thermalresponse will change depending on the circuit board design.

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